

## Keynote Speaker

**Martin Kuball** (Univ. of Bristol),  
“Unleashing the power of diamond – Heterogenous integrations”

## Invited Speakers (tentative)

- 1) **Keisuke Shinohara**, Teledyne Scientific & Imaging, “*Multi 2DEG Channel BRIDGE HEMT Technology for Millimeter-Wave Power Amplifier and RF Switch Applications*”
- 2) **Edward Chang**, National Chiao Tung Univ., “*A High Current E-mode GaN HEMT with Thin Barrier Layer*”
- 3) **Dinesh Ramanathan**, NEXGEN, “*Reinventing Power Electronics: NexGen Power Systems with NexGen Vertical GaN™*”
- 4) **Rongming Chu**, Pennsylvania State Univ., “*Opportunities and Challenges of GaN Super-Heterojunction (Tentative)*”
- 5) **Uttam Singisett**, Univ. at Buffalo, “*Gallium oxides lateral devices: kV power transistor to high power switched mode RF amplifiers*”
- 6) **Heiji Watanabe**, Osaka Univ., “*Interface science and engineering for GaN-based MOS devices*”
- 7) **Tsunenobu Kimoto**, Kyoto Univ., “*High Mobility in SiC MOSFETs with Heavily-Doped p-Bodie*”
- 8) **Xufang Zhang**, Kanazawa Univ., “*Recent Progress in Electrical Characterization of Al<sub>2</sub>O<sub>3</sub>/Diamond Interface*”
- 9) **Makoto Kasu**, Saga Univ., “*Diamond 2-Inch-Wafer Growth and 875-MW/cm<sup>2</sup> Power FET*”
- 10) **Colombo Bolognesi**, ETH Zurich, “*InP/GaAsSb DHBTs: Historical Evolution, Device Physics, and State-of-the-Art Performance*”
- 11) **Takuya Hoshi**, NTT, “*Recent Progress in Metal-Organic Vapor Phase Epitaxy of InP-based Ultrahigh-Speed Transistors*”
- 12) **Michael Feiginov**, Technical Univ. of Vienna, “*Sub-THz and THz Double-Resonant-Tunnelling-Diode Patch-Antenna Oscillators*”

- 13) **Eduardo M Chumbes**, Raytheon Missiles & Defense, “*ScAlN/GaN Heterojunction Field Effect Transistors for Ultra-high power and efficient RF Power Amplifiers*”
- 14) **Joachim Würfl**, Ferdinand-Braun-Institut, “*AlN based devices for new power electronic switches and mm-wave power MMICs*”
- 15) **Hyeon-Bhin Jo**, Kyungpook National Univ., “*In<sub>0.53</sub>Ga<sub>0.47</sub>As Multi-Bridge Channel Field-Effect-Transistors for future CMOS applications*”
- 16) **Yoshio Honda**, Nagoya Univ., “*Correlation between Dislocation and Reverse Leakage Current in GaN pn Junction*”
- 17) **Manabu Arai**, Nagoya Univ.